

**Search Notes**

Application/Control No.

10/710,724

Examiner

Russell M. Kobert

Applicant(s)/Patent under  
Reexamination

KANG ET AL.

Art Unit

2829

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference Search History Printout		11/26/2005	RK

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) - see search history printout(s)	11/23/2005	RK
324/765,769,158.1; class 716; class 438; class 702 (text search only - see search history printout)	11/23/2005	RK
Internet search - search string "wafer and test and (stress-induced degradation or SLIC) and pdf"	11/23/2005	RK
Internet search - search string "(stress-induced degradation or SLIC) and ratio and pdf"	11/23/2005	RK